

Solid State Devices, Inc.

14701 Firestone Blvd * La Mirada, Ca 90638 Phone: (562) 404-4474 * Fax: (562) 404-1773 ssdi@ssdi-power.com * www.ssdi-power.com

Designer's Data Sheet

Part Number/Ordering Information 1/

SGF43E70

L Screening^{2/}
= Not Screened
TX = TX Level
TXV = TXV Level

S = S Level

Package -28 = LCC28

SGF43E70-28

43 AMP GaN FET Normally-Off 700 VOLTS, 39 mΩ typical

FEATURES:

- 3rd Generation Gallium Nitride Technology
- Combines GaN HEMT and Low Voltage Si MOSFET (Cascode) for Superior Performance
- · Works with Common Gate Drivers
- Low RDSon
- Low Q_q Simplifies Gate Drive Circuit
- Very Fast Switching for High Frequency Applications
- Low Thermal Resistance Internal Heat Sink
- Hermetically Sealed Surface Mount Package
- Extremely Small Footprint and Low Profile
- $\bullet\,$ TX, TXV, and S-Level Screening Available $^{2\!/}$
- Available as Normally-On (without the Si Mosfet Driver)

APPLICATIONS:

- · High Efficiency DC-DC / PoL Converters
- Motor Controller
- Military and Aerospace

BENEFITS:

- GaN Transistor offers superior advantages over Si based MOSFET: low Q_{RR}, low gate charge, low R_{DS(ON)}, fast switching speed and low temperature coefficient
- · Benefits circuit designer through higher efficiency, lower cross-over losses and On-state losses
- Eliminates the need to add free-wheeling diode

Maximum Ratings ^{3/}	Symbol	Value	Unit	
Continuous Drain - Source Voltage	$V_{ exttt{DSS}}$	700	V	
Transient Drain - Source Voltage In off-state, spike duty cycle D < 0.01, spike duration	V _{TDS}	800	V	
Gate – Source Voltage		V_{GS}	±20	٧
Continuous Drain Current	T _C = 25°C	I _{D1}	43	Α
	T _C = 100°C	I _{D2}	23	Α
Pulsed Drain Current (Top / Pwidth limited)	Pulse width = 10 μs	I _{D3}	240	Α
Total Power Dissipation	P_{D}	83	W	
Operating & Storage Temperature	T _{OP} & T _{STG}	-55 to +150	°C	
Thermal Resistance (Junction to Case)	$R_{ heta JC}$	1.5	°C/W	

NOTES:

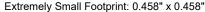
- <u>1</u>/ For ordering information, price, operating curves, and availabilitycontact factory.
- 2/ Screening based on MIL-PRF-19500. Screening flows available on request.
- 3/ Unless otherwise specified, all electrical characteristics @ 25°C.
- 4/ Pulse test, $P_W = 300 \mu s$, D.C. = 2%.

LCC28



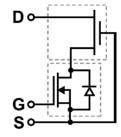






Low Profile: .095" max (dime used for size reference)

Cascode Device Structure



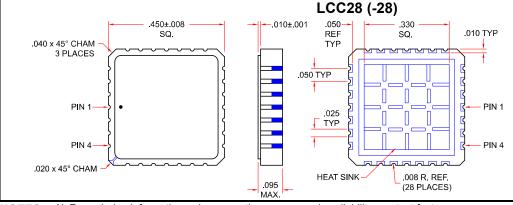


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Electrical Characteristics ^{3/}		Symbol	Min	Тур	Max	Unit
Drain to Source Breakdown Voltage	$I_D = 100 \ \mu A, \ V_{GS} = 0 \ V$	V _{DSS}	700	-	-	V
Gate to Source Leakage	$V_{GS} = 20V$ $V_{GS} = -20V$	I _{GSSF} I _{GSSR}	-	1 1	400 -400	nA
Drain to Source Leakage Current V_{DS} = 650 V, V_{GS} = 0 V	$T_{J} = 25^{\circ}C$ $T_{J} = 150^{\circ}C$	I _{DSS}	-	3 15	25 -	μΑ
Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 1mA$	$V_{GS(th)}$	3.3	4	4.8	٧
Drain to Source On State Resistance ^{4/} $V_{GS} = 10 \text{ V}, I_D = 30 \text{ A}$	T _J = 25°C T _J = 150°C	R _{DS(on)}	- -	39 76	45 -	mΩ
Total Gate Charge Gate to Source Charge Gate to Drain Charge	$V_{DS} = 400 \text{ V}$ $I_{D} = 32 \text{ A}$	$egin{array}{c} \mathbf{Q}_{\mathrm{g}} \ \mathbf{Q}_{\mathrm{gd}} \end{array}$	- - -	24 10 6	36 - -	nC
Total Output Charge	$V_{GS} = 0 \text{ V}, V_{DS} = 0 \text{ V} - 400 \text{ V}$	Q _{oss}	-	178	-	nC
Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{GS} = 0 V$ $V_{DS} = 400 V$ f = 1 MHz	C _{iss} C _{oss} C _{rss}	- - -	1500 190 10	1 1 1	pF
Output Capacitance, Energy Related	V _{GS} = 0 V, V _{DS} = 0 V - 400 V	C _{O(er)}	-	290	-	pF
Output Capacitance, Time Related	$V_{GS} = 0 \text{ V}, V_{DS} = 0 \text{ V} - 400 \text{ V}$	C _{O(er)}	-	440	-	рF
Turn-on Delay Rise Time Turn-off Delay Fall Time	V_{DS} = 400 V V_{GS} = 12 V I_{D} = 32 A R_{G} = 30 Ω	$egin{array}{c} egin{array}{c} \egin{array}{c} \egin{array}{c} \egin{array}{c} \egin{array}$	- - -	69 14 99 12		ns
Source to Drain Forward Current ^{4/}	$V_{GS} = 0 \text{ V}, T_{C} = 100^{\circ}\text{C}$	I _{SD}	-	-	29.5	Α
Source to Drain Forward Voltage ^{4/}	$I_S = 32 \text{ A}, V_{GS} = 0 \text{ V}$ $I_S = 15 \text{ A}, V_{GS} = 0 \text{ V}$	V _{SD}	- -	2.1 1.4		V
Source to Drain Reverse Recovery Time	$I_S = 30 \text{ A}, V_{DD} = 400 \text{ V}$ di/dt=1000 A/us	t _{RR}	-	65	-	ns
Source to Drain Reverse Recovery Charg	ge $I_S = 30 \text{ A}, V_{DD} = 400 \text{ V}$ di/dt=1000 A/us	\mathbf{Q}_{RR}	-	178	-	nC



PIN ASSIGNMENT			
Source*	12 - 18		
Drain*	1 – 5, 27, 28		
Gate	9		
Substrate**	19, heat sink		
GaN Gate**	11, 20		
*All Dunin / Course mine mount ha			

*All Drain / Source pins must be connected to maximize current capability and minimize $R_{\text{DS}(\text{ON})}$ **Connect to SOURCE

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